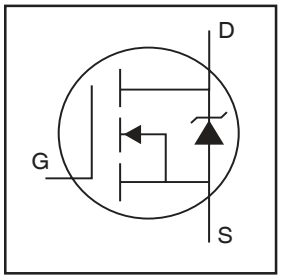
PD - 91309C

International
IOR Rectifier

IRF3710

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated



V_{DSS} = 100V

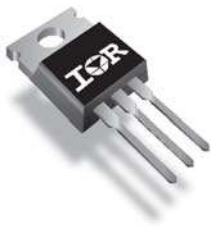
$R_{DS(on)}$ = 23mΩ

I_D = 57A

Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



TO-220AB

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ T_C = 25°C	Continuous Drain Current, V_{GS} @ 10V	57	A
I_D @ T_C = 100°C	Continuous Drain Current, V_{GS} @ 10V	40	
I_{DM}	Pulsed Drain Current ①	230	
P_D @T_C = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
I_{AR}	Avalanche Current①	28	A
E_{AR}	Repetitive Avalanche Energy①	20	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.8	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	——	0.75	°C/W
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface	0.50	——	
$R_{\theta JA}$	Junction-to-Ambient	——	62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100	—	—	V	V_{GS} = 0V, I_D = 250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.13	—	V/°C	Reference to 25°C, I_D = 1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	—	23	mΩ	V_{GS} = 10V, I_D =28A ④
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	V_{DS} = V_{GS}, I_D = 250µA
g_{fs}	Forward Transconductance	32	—	—	S	V_{DS} = 25V, I_D = 28A④
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	µA	V_{DS} = 100V, V_{GS} = 0V
		—	—	250		V_{DS} = 80V, V_{GS} = 0V, T_J = 150°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	100	nA	V_{GS} = 20V
	Gate-to-Source Reverse Leakage	—	—	-100		V_{GS} = -20V
Q_g	Total Gate Charge	—	—	130	nC	I_D = 28A
Q_{gs}	Gate-to-Source Charge	—	—	26		V_{DS} = 80V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	43		V_{GS} = 10V, See Fig. 6 and 13
$t_{d(on)}$	Turn-On Delay Time	—	12	—	ns	V_{DD} = 50V
t_r	Rise Time	—	58	—		I_D = 28A
$t_{d(off)}$	Turn-Off Delay Time	—	45	—		R_G = 2.5Ω
t_f	Fall Time	—	47	—		V_{GS} = 10V, See Fig. 10 ④
L_D	Internal Drain Inductance	—	4.5	—	nH	Between lead, 6mm (0.25in.) from package and center of die contact
L_S	Internal Source Inductance	—	7.5	—		
C_{iss}	Input Capacitance	—	3130	—	pF	V_{GS} = 0V
C_{oss}	Output Capacitance	—	410	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	72	—		f = 1.0MHz, See Fig. 5
E_{AS}	Single Pulse Avalanche Energy②	—	1060③	280⑥	mJ	I_{AS} = 28A, L = 0.70mH

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	57	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode)①	—	—	230		
V_{SD}	Diode Forward Voltage	—	—	1.2	V	T_J = 25°C, I_S = 28A, V_{GS} = 0V ④
t_{rr}	Reverse Recovery Time	—	140	220	ns	T_J = 25°C, I_F = 28A
Q_{rr}	Reverse Recovery Charge	—	670	1010	nC	di/dt = 100A/µs ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)				

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

② Starting T_J = 25°C, L = 0.70mH
R_G = 25Ω, I_{AS} = 28A, V_{GS}=10V (See Figure 12)

③ I_{SD} ≤ 28A, di/dt ≤ 380A/µs, V_{DD} ≤ $V_{(BR)DSS}$, T_J ≤ 175°C

④ Pulse width ≤ 400µs; duty cycle ≤ 2%.

⑤ This is a typical value at device destruction and represents operation outside rated limits.

⑥ This is a calculated value limited to T_J = 175°C .